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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	20
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 12x14b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-VFQFN Exposed Pad
Supplier Device Package	24-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb11f16es0-b-qfn24

3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 24.5 MHz oscillator divided by 8.

The clock control system offers the following features:

- Provides clock to core and peripherals.
- 24.5 MHz internal oscillator (HFOSC0), accurate to $\pm 2\%$ over supply and temperature corners.
- 72 MHz internal oscillator (HFOSC1), accurate to $\pm 2\%$ over supply and temperature corners.
- 80 kHz low-frequency oscillator (LFOSC0).
- External RC, CMOS, and high-frequency crystal clock options (EXTCLK).
- Clock divider with eight settings for flexible clock scaling:
 - Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.
 - HFOSC0 and HFOSC1 include 1.5x pre-scalers for further flexibility.

3.5 Counters/Timers and PWM

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- 16-bit time base
- Programmable clock divisor and clock source selection
- Up to six independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (center or edge-aligned operation)
- Output polarity control
- Frequency output mode
- Capture on rising, falling or any edge
- Compare function for arbitrary waveform generation
- Software timer (internal compare) mode
- Can accept hardware “kill” signal from comparator 0 or comparator 1

Timers (Timer 0, Timer 1, Timer 2, Timer 3, Timer 4, and Timer 5)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2, Timer 3, Timer 4, and Timer 5 are 16-bit timers including the following features:

- Clock sources for all timers include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8
- LFOSC0 divided by 8 may be used to clock Timer 3 and Timer 4 in active or suspend/snooze power modes
- Timer 4 is a low-power wake source, and can be chained together with Timer 3
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture
- LFOSC0 capture
- Comparator 0 capture
- Configurable Logic output capture

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions.
- Baud rates up to $\text{SYSCLK}/2$ (transmit) or $\text{SYSCLK}/8$ (receive).
- 8- or 9-bit data.
- Automatic start and stop generation.
- Single-byte FIFO on transmit and receive.

Universal Asynchronous Receiver/Transmitter (UART1)

UART1 is an asynchronous, full duplex serial port offering a variety of data formatting options. A dedicated baud rate generator with a 16-bit timer and selectable prescaler is included, which can generate a wide range of baud rates. A received data FIFO allows UART1 to receive multiple bytes before data is lost and an overflow occurs.

UART1 provides the following features:

- Asynchronous transmissions and receptions
- Dedicated baud rate generator supports baud rates up to $\text{SYSCLK}/2$ (transmit) or $\text{SYSCLK}/8$ (receive)
- 5, 6, 7, 8, or 9 bit data
- Automatic start and stop generation
- Automatic parity generation and checking
- Single-byte buffer on transmit and receive
- Auto-baud detection
- LIN break and sync field detection
- CTS / RTS hardware flow control

Serial Peripheral Interface (SPI0)

The serial peripheral interface (SPI) module provides access to a flexible, full-duplex synchronous serial bus. The SPI can operate as a master or slave device in both 3-wire or 4-wire modes, and supports multiple masters and slaves on a single SPI bus. The slave-select (NSS) signal can be configured as an input to select the SPI in slave mode, or to disable master mode operation in a multi-master environment, avoiding contention on the SPI bus when more than one master attempts simultaneous data transfers. NSS can also be configured as a firmware-controlled chip-select output in master mode, or disabled to reduce the number of pins required. Additional general purpose port I/O pins can be used to select multiple slave devices in master mode.

- Supports 3- or 4-wire master or slave modes
- Supports external clock frequencies up to 12 Mbps in master or slave mode
- Support for all clock phase and polarity modes
- 8-bit programmable clock rate (master)
- Programmable receive timeout (slave)
- Two byte FIFO on transmit and receive
- Can operate in suspend or snooze modes and wake the CPU on reception of a byte
- Support for multiple masters on the same data lines

System Management Bus / I2C (SMB0)

The SMBus I/O interface is a two-wire, bi-directional serial bus. The SMBus is compliant with the System Management Bus Specification, version 1.1, and compatible with the I²C serial bus.

The SMBus module includes the following features:

- Standard (up to 100 kbps) and Fast (400 kbps) transfer speeds
- Support for master, slave, and multi-master modes
- Hardware synchronization and arbitration for multi-master mode
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave and general call address recognition
- Firmware support for 10-bit slave address decoding
- Ability to inhibit all slave states
- Programmable data setup/hold times
- Transmit and receive FIFOs (one byte) to help increase throughput in faster applications

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in [Table 4.1 Recommended Operating Conditions on page 14](#), unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V _{DD}		2.2	—	3.6	V
Operating Supply Voltage on VIO ^{2, 3}	V _{IO}		2.2	—	V _{DD}	V
System Clock Frequency	f _{SYSCLK}		0	—	73.5	MHz
Operating Ambient Temperature	T _A		-40	—	105	°C

Note:

1. All voltages with respect to GND
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.
3. GPIO levels are undefined whenever VIO is less than 1 V.

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V _{VDDM}		1.95	2.05	2.15	V
Power-On Reset (POR) Threshold	V _{POR}	Rising Voltage on VDD	—	1.4	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t _{RMP}	Time to V _{DD} > 2.2 V	10	—	—	μs
Reset Delay from POR	t _{POR}	Relative to V _{DD} > V _{POR}	3	10	31	ms
Reset Delay from non-POR source	t _{RST}	Time between release of reset source and code execution	—	50	—	μs
RST Low Time to Generate Reset	t _{RSTL}		15	—	—	μs
Missing Clock Detector Response Time (final rising edge to reset)	t _{MCD}	F _{SYSClk} > 1 MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F _{MCD}		—	7.5	13.5	kHz
VDD Supply Monitor Turn-On Time	t _{MON}		—	2	—	μs

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time ^{1,2}	t _{WRITE}	One Byte, F _{SYSClk} = 24.5 MHz	19	20	21	μs
Erase Time ^{1,2}	t _{ERASE}	One Page, F _{SYSClk} = 24.5 MHz	5.2	5.35	5.5	ms
V _{DD} Voltage During Programming ³	V _{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N _{WE}		20k	100k	—	Cycles
CRC Calculation Time	t _{CRC}	One 256-Byte Block SYSClk = 48 MHz	—	5.5	—	μs

Note:

- Does not include sequencing time before and after the write/erase operation, which may be multiple SYSClk cycles.
- The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
- Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).
- Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.8 Crystal Oscillator

Table 4.8. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	—	25	MHz
Crystal Drive Current	I_{XTAL}	XFCN = 0	—	0.5	—	μA
		XFCN = 1	—	1.5	—	μA
		XFCN = 2	—	4.8	—	μA
		XFCN = 3	—	14	—	μA
		XFCN = 4	—	40	—	μA
		XFCN = 5	—	120	—	μA
		XFCN = 6	—	550	—	μA
		XFCN = 7	—	2.6	—	mA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Supply Rejection Ratio	PSRR _{ADC}	At 1 kHz	—	66	—	dB
		At 1 MHz	—	43	—	dB
DC Performance						
Integral Nonlinearity	INL	14 Bit Mode	-3.5 ⁴	-1.2 / +5	8.5 ⁴	LSB
		12 Bit Mode	-1.9	-0.35 / +1	1.9	LSB
		10 Bit Mode	-0.6	±0.2	0.6	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	14 Bit Mode	-1 ⁴	±1	2.5 ⁴	LSB
		12 Bit Mode	-0.9	±0.3	0.9	LSB
		10 Bit Mode	-0.5	±0.2	0.5	LSB
Offset Error ⁵	E _{OFF}	14 Bit Mode	-8 ⁴	-2.5	8 ⁴	LSB
		12 Bit Mode	-2	0	2	LSB
		10 Bit Mode	-1	0	1	LSB
Offset Temperature Coefficient	TC _{OFF}		—	0.011	—	LSB/°C
Slope Error	E _M	14 Bit Mode	-15 ⁴	—	15 ⁴	LSB
		12 Bit Mode	-2.6	—	2.6	LSB
		10 Bit Mode	-1.1	—	1.1	LSB
Dynamic Performance 10 kHz Sine Wave Input 1 dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	14 Bit Mode	66 ⁴	72	—	dB
		12 Bit Mode	64	68	—	dB
		10 Bit Mode	59	61	—	dB
Signal-to-Noise Plus Distortion	SNDR	14 Bit Mode	66 ⁴	72	—	dB
		12 Bit Mode	64	68	—	dB
		10 Bit Mode	59	61	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	14 Bit Mode	—	-74	—	dB
		12 Bit Mode	—	-72	—	dB
		10 Bit Mode	—	-69	—	dB
Spurious-Free Dynamic Range	SFDR	14 Bit Mode	—	74	—	dB
		12 Bit Mode	—	74	—	dB
		10 Bit Mode	—	71	—	dB

Note:

1. This time is equivalent to four periods of a clock running at 18 MHz + 2%.
2. Conversion Time does not include Tracking Time. Total Conversion Time is:

$$\text{Total Conversion Time} = [\text{RPT} \times (\text{ADTK} + \text{NUMBITS} + 1) \times \text{T}(\text{SARCLK})] + (\text{T}(\text{ADCCLK}) \times 4)$$

where RPT is the number of conversions represented by the ADRPT field and ADCCLK is the clock selected for the ADC.
3. Absolute input pin voltage is limited by the V_{IO} supply.
4. Measured with characterization data and not production tested.
5. The offset is determined using curve fitting since the specification is measured using linear search where the intercept is always positive.

4.1.10 Voltage Reference

Table 4.10. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}		1.62	1.65	1.68	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	μs
Power Supply Rejection	$PSRR_{\text{REFFS}}$		—	400	—	ppm/V
On-chip Precision Reference						
Valid Supply Range	V_{DD}	1.2 V Output	2.2	—	3.6	V
		2.4 V Output	2.7	—	3.6	V
Output Voltage	V_{REFP}	1.2 V Output, $V_{\text{DD}} = 3.3 \text{ V}$, $T = 25 \text{ °C}$	1.195	1.2	1.205	V
		1.2 V Output	1.18	1.2	1.22	V
		2.4 V Output, $V_{\text{DD}} = 3.3 \text{ V}$, $T = 25 \text{ °C}$	2.39	2.4	2.41	V
		2.4 V Output	2.36	2.4	2.44	V
Turn-on Time, settling to 0.5 LSB	t_{VREFP}	4.7 μF tantalum + 0.1 μF ceramic bypass on VREF pin	—	3	—	ms
		0.1 μF ceramic bypass on VREF pin	—	100	—	μs
Load Regulation	LR_{VREFP}	$V_{\text{REF}} = 2.4 \text{ V}$, Load = 0 to 200 μA to GND	—	8	—	μV/μA
		$V_{\text{REF}} = 1.2 \text{ V}$, Load = 0 to 200 μA to GND	—	5	—	μV/μA
Load Capacitor	C_{VREFP}	Load = 0 to 200 μA to GND	0.1	—	—	μF
Short-circuit current	ISC_{VREFP}		—	—	8	mA
Power Supply Rejection	$PSRR_{\text{VREFP}}$		—	75	—	dB
External Reference						
Input Current	I_{EXTREF}	ADC Sample Rate = 1 Msps; $V_{\text{REF}} = 3.0 \text{ V}$	—	5	—	μA

4.1.11 Temperature Sensor

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	V_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	751	—	mV
Uncalibrated Offset Error ¹	E_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	19	—	mV
Slope	M		—	2.82	—	mV/ $^{\circ}\text{C}$
Slope Error ¹	E_M		—	29	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity	LIN	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	—	-0.1 to 0.15	—	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	—	-0.2 to 0.35	—	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	—	-0.4 to 0.8	—	$^{\circ}\text{C}$
Turn-on Time	t_{ON}		—	3.5	—	μs
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset ^{2, 3}	E_{TOT}	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	-2.6	—	1.8	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-2.9	—	2.7	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	-3.2	—	4.2	$^{\circ}\text{C}$

Note:

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. The temp sensor error includes the offset calibration error, slope error, and linearity error. The values are based upon characterization and are not tested across temperature in production. The values represent three standard deviations above and below the mean. Additional information on achieving high measurement accuracy is available in AN929: Accurate Temperature Sensing with the EFM8 Laser Bee MCU Family.

4.1.15 Port I/O

Table 4.15. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	$I_{OH} = -7 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	$V_{IO} - 0.7$	—	—	V
		$I_{OH} = -3.3 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	$V_{IO} \times 0.8$	—	—	V
		$I_{OH} = -1.8 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output Low Voltage (High Drive)	V_{OL}	$I_{OL} = 13.5 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	—	—	0.6	V
		$I_{OL} = 7 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	—	—	$V_{IO} \times 0.2$	V
		$I_{OL} = 3.6 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output High Voltage (Low Drive)	V_{OH}	$I_{OH} = -4.75 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	$V_{IO} - 0.7$	—	—	V
		$I_{OH} = -2.25 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	$V_{IO} \times 0.8$	—	—	V
		$I_{OH} = -1.2 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output Low Voltage (Low Drive)	V_{OL}	$I_{OL} = 6.5 \text{ mA}$, $V_{IO} \geq 3.0 \text{ V}$	—	—	0.6	V
		$I_{OL} = 3.5 \text{ mA}$, $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	—	—	$V_{IO} \times 0.2$	V
		$I_{OL} = 1.8 \text{ mA}$, $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Input High Voltage	V_{IH}		$0.7 \times V_{IO}$	—	—	V
Input Low Voltage	V_{IL}		—	—	$0.3 \times V_{IO}$	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current ($V_{IN} = 0 \text{ V}$)	I_{PU}	$V_{DD} = 3.6$	-30	-20	-10	μA
Input Leakage (Pullups off or Analog)	I_{LK}	$\text{GND} < V_{IN} < V_{IO}$	-1.1	—	4	μA
Input Leakage Current with V_{IN} above V_{IO}	I_{LK}	$V_{IO} < V_{IN} < V_{IO} + 2.5 \text{ V}$ Any pin except P3.0, P3.1, P3.2, or P3.3	0	5	150	μA

Table 4.17. SMBus Peripheral Timing Formulas (Master Mode)

Parameter	Symbol	Clocks
SMBus Operating Frequency	f_{SMB}	$f_{\text{CSO}} / 3$
Bus Free Time Between STOP and START Conditions	t_{BUF}	$2 / f_{\text{CSO}}$
Hold Time After (Repeated) START Condition	$t_{\text{HD:STA}}$	$1 / f_{\text{CSO}}$
Repeated START Condition Setup Time	$t_{\text{SU:STA}}$	$2 / f_{\text{CSO}}$
STOP Condition Setup Time	$t_{\text{SU:STO}}$	$2 / f_{\text{CSO}}$
Clock Low Period	t_{LOW}	$1 / f_{\text{CSO}}$
Clock High Period	t_{HIGH}	$2 / f_{\text{CSO}}$

Note:
1. f_{CSO} is the SMBus peripheral clock source overflow frequency.

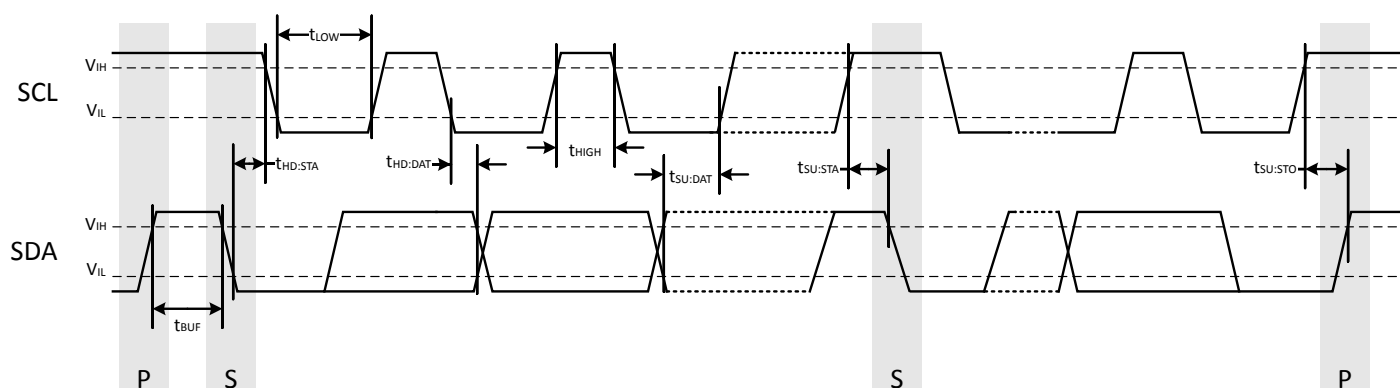


Figure 4.1. SMBus Peripheral Timing Diagram (Master Mode)

4.2 Thermal Conditions

Table 4.18. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance	θ_{JA}	QFN24 Packages	—	30	—	°C/W
		QFN32 Packages	—	26	—	°C/W
		QFP32 Packages	—	80	—	°C/W
		QSOP24 Packages	—	65	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

Table 6.1. Pin Definitions for EFM8LB1x-QFN32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	VIO	I/O Supply Power Input			
3	VDD	Supply Power Input			
4	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
5	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
6	P3.4	Multifunction I/O			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
6	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5
15	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU2OUT CLU1A.15 CLU2B.14 CLU3A.14	ADC0.15 CMP1P.4 CMP1N.4
16	P2.1	Multifunction I/O	Yes	P2MAT.1 I2C0_SCL CLU1B.14 CLU2A.15 CLU3B.15	ADC0.14 CMP1P.3 CMP1N.3
17	P2.0	Multifunction I/O	Yes	P2MAT.0 I2C0_SDA CLU1A.14 CLU2A.14 CLU3B.14	CMP1P.2 CMP1N.2

6.4 EFM8LB1x-QSOP24 Pin Definitions

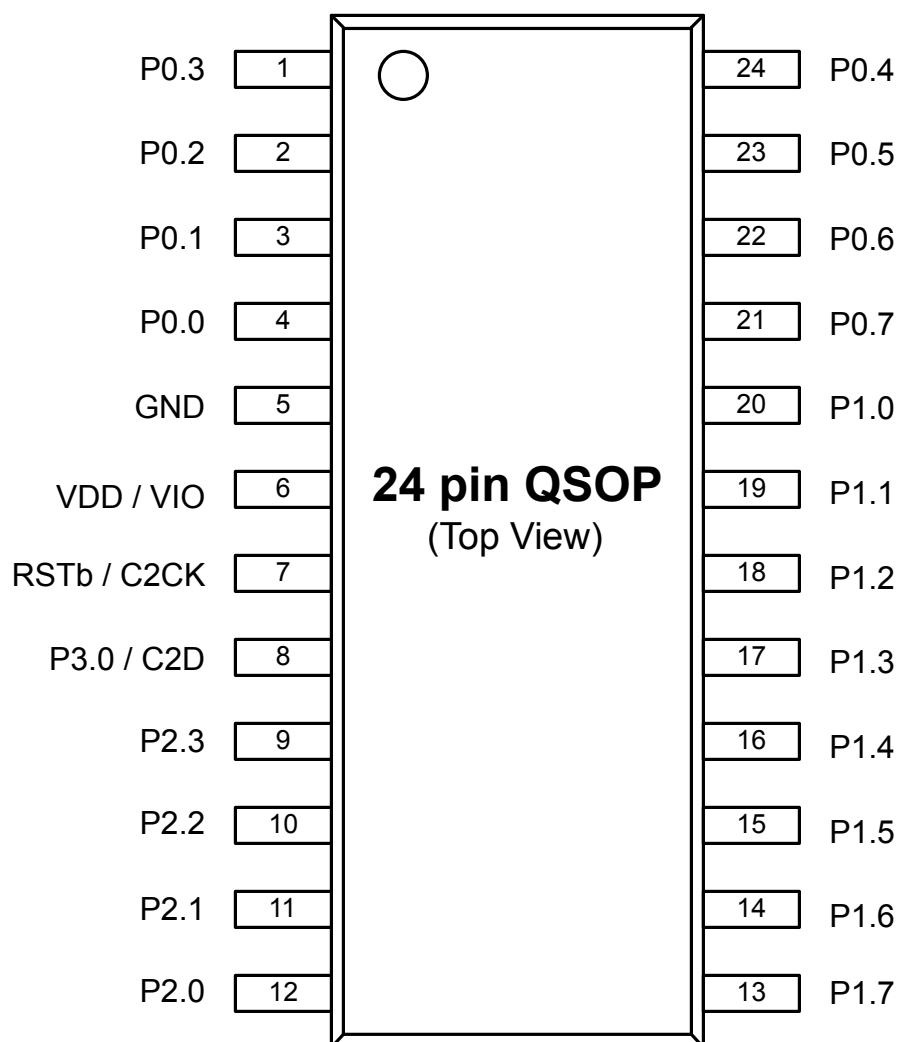


Figure 6.4. EFM8LB1x-QSOP24 Pinout

Table 6.4. Pin Definitions for EFM8LB1x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.9 CLU3A.9	XTAL2

7. QFN32 Package Specifications

7.1 QFN32 Package Dimensions

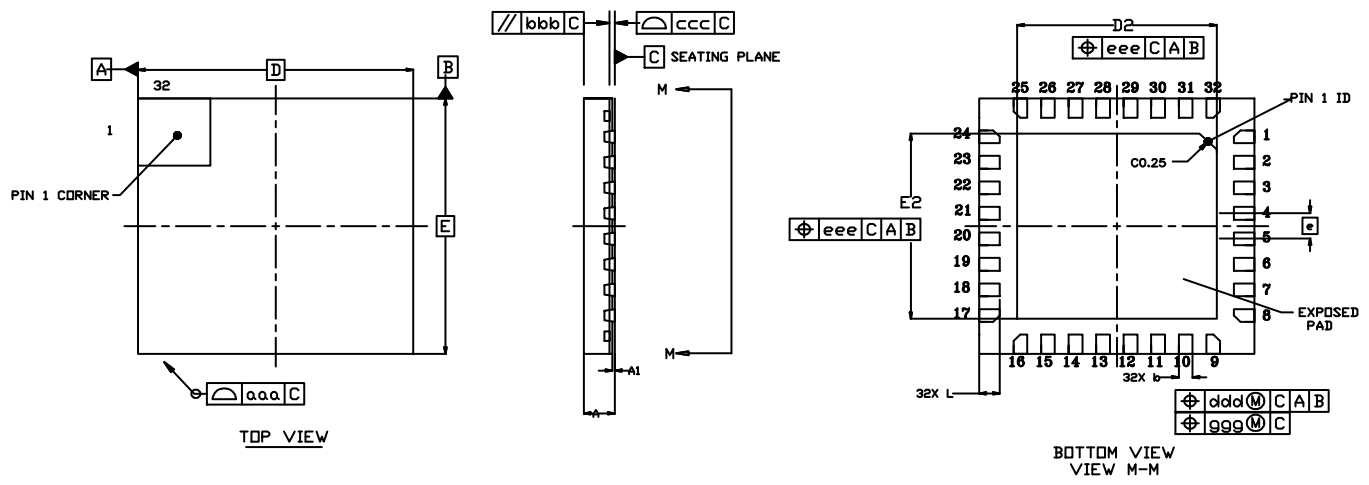


Figure 7.1. QFN32 Package Drawing

Table 7.1. QFN32 Package Dimensions

Dimension	Min	Typ	Max
A	0.45	0.50	0.55
A1	0.00	0.035	0.05
b	0.15	0.20	0.25
D	4.00 BSC.		
D2	2.80	2.90	3.00
e	0.40 BSC.		
E	4.00 BSC.		
E2	2.80	2.90	3.00
L	0.20	0.30	0.40
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10
ggg	—	—	0.05

Dimension	Min	Max
Note: <ol style="list-style-type: none"> 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification. 3. This Land Pattern Design is based on the IPC-7351 guidelines. 4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm. 5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad. 6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release. 7. The stencil thickness should be 0.125 mm (5 mils). 8. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads. 9. A 2 x 2 array of 1.10 mm square openings on a 1.30 mm pitch should be used for the center pad. 10. A No-Clean, Type-3 solder paste is recommended. 11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components. 		

7.3 QFN32 Package Marking



Figure 7.3. QFN32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Typ	Max
aaa	0.20		
bbb	0.20		
ccc	0.10		
ddd	0.20		
theta	0°	3.5°	7°
Note: <ol style="list-style-type: none"> 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994. 3. This drawing conforms to JEDEC outline MS-026. 4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components. 			

9. QFN24 Package Specifications

9.1 QFN24 Package Dimensions

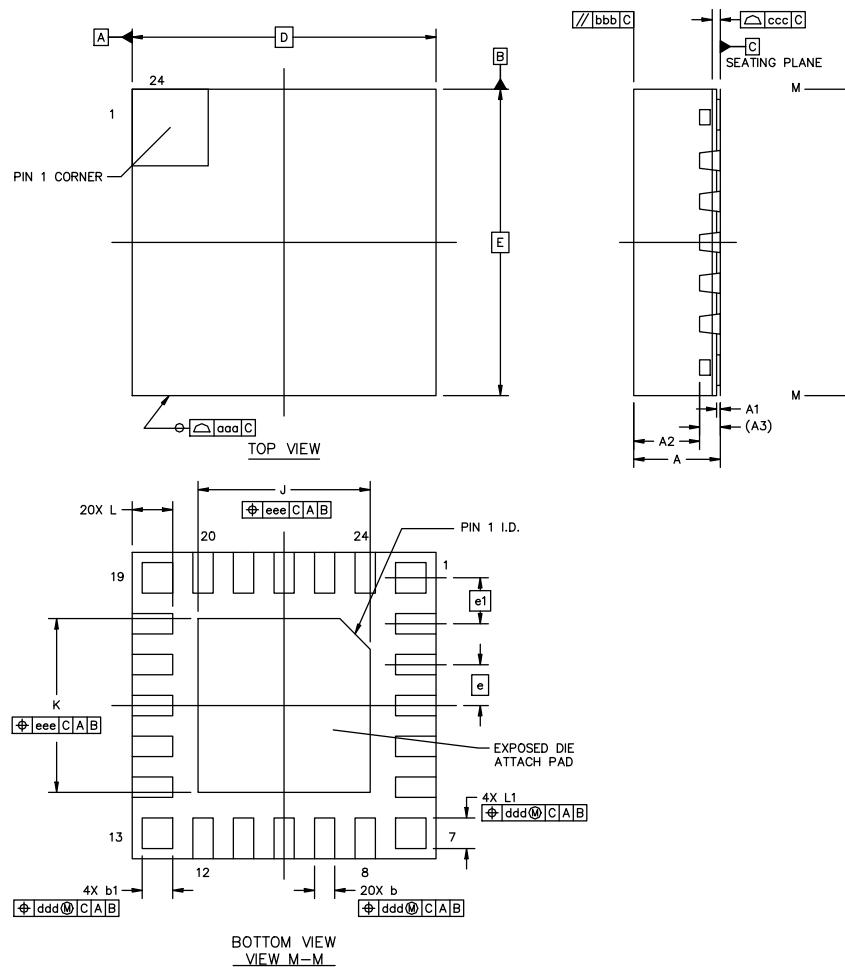


Figure 9.1. QFN24 Package Drawing

Table 9.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.8	0.85	0.9
A1	0.00	—	0.05
A2	—	0.65	—
A3	0.203 REF		
b	0.15	0.2	0.25
b1	0.25	0.3	0.35
D	3.00 BSC		
E	3.00 BSC		

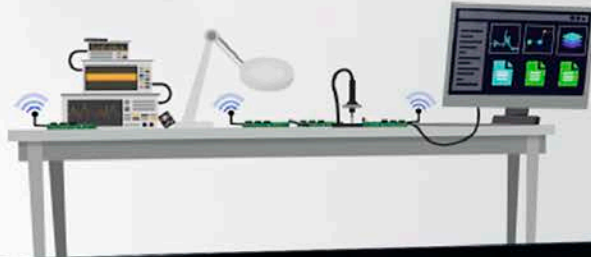
Dimension	Min	Typ	Max
e	0.40 BSC		
e1	0.45 BSC		
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

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